

Notice of References Cited

Application/Control No.

10/572,506

Applicant(s)/Patent Under
Reexamination
JEON ET AL.

Examiner

Kwang Han

Art Unit

1795

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,746,798	06-2004	Hiratsuka et al.	429/163
*	B	US-5,279,623	01-1994	Watanabe et al.	29/25.03
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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